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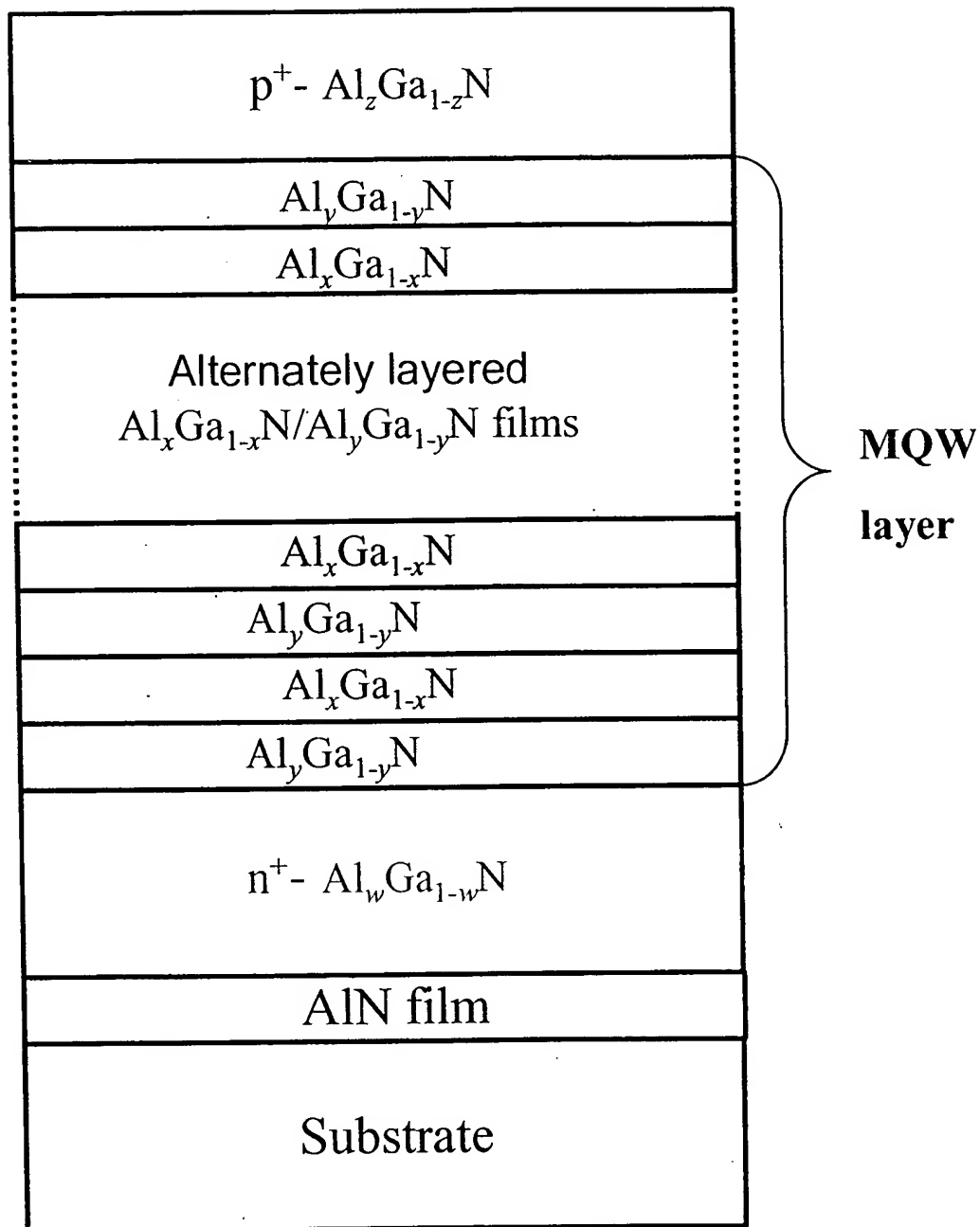


FIG. 1

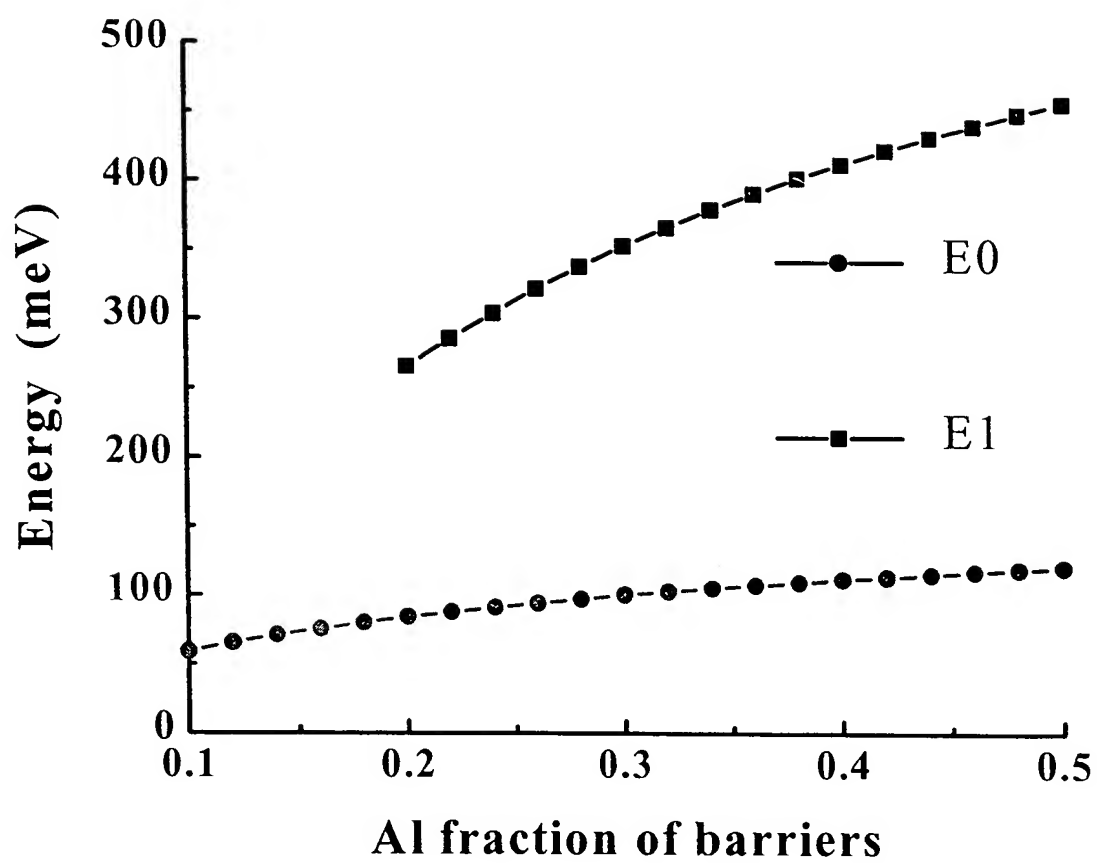


FIG. 2

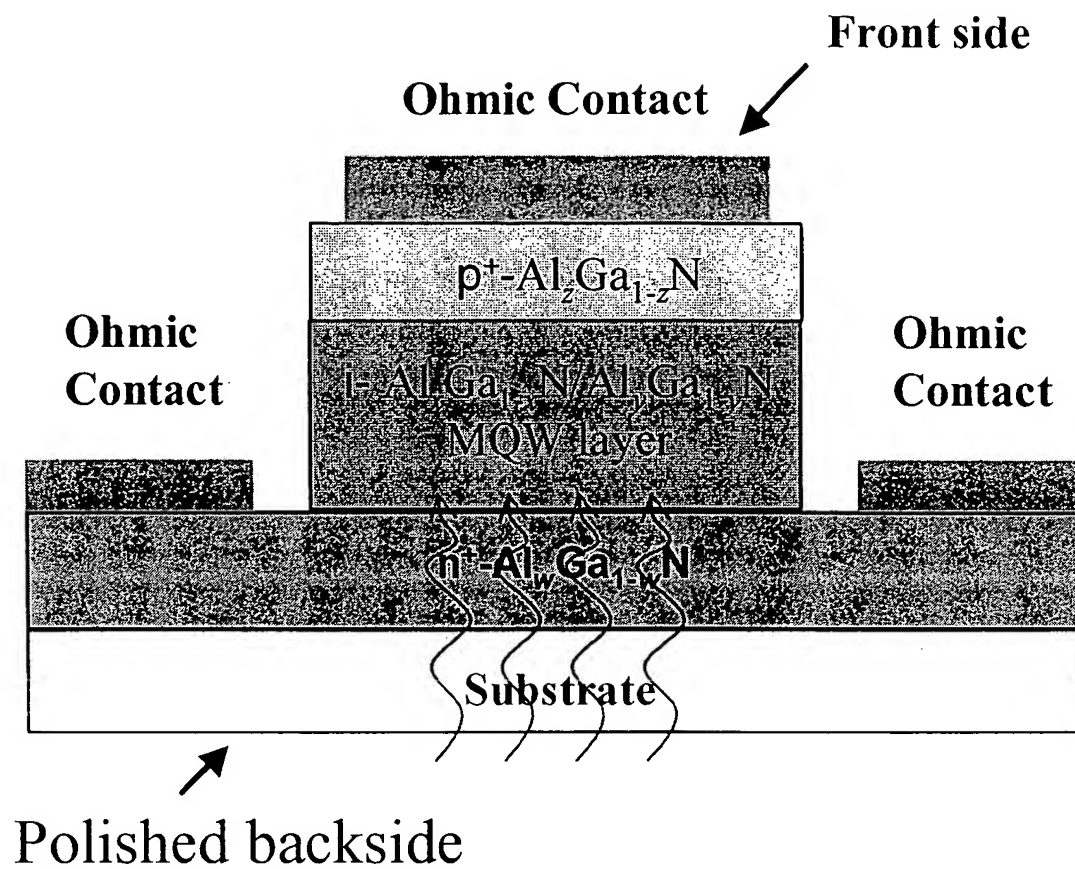


FIG. 3

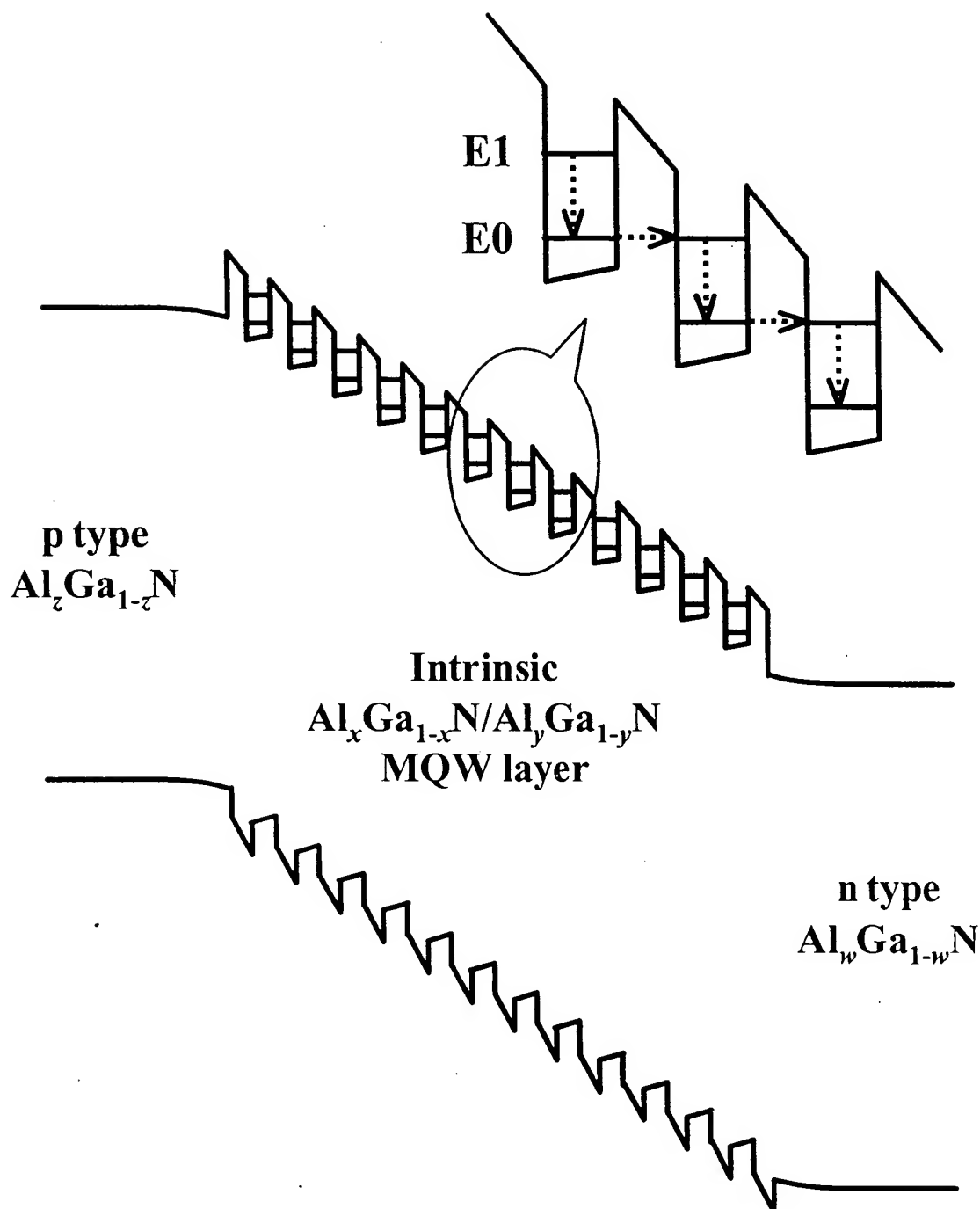


FIG. 4

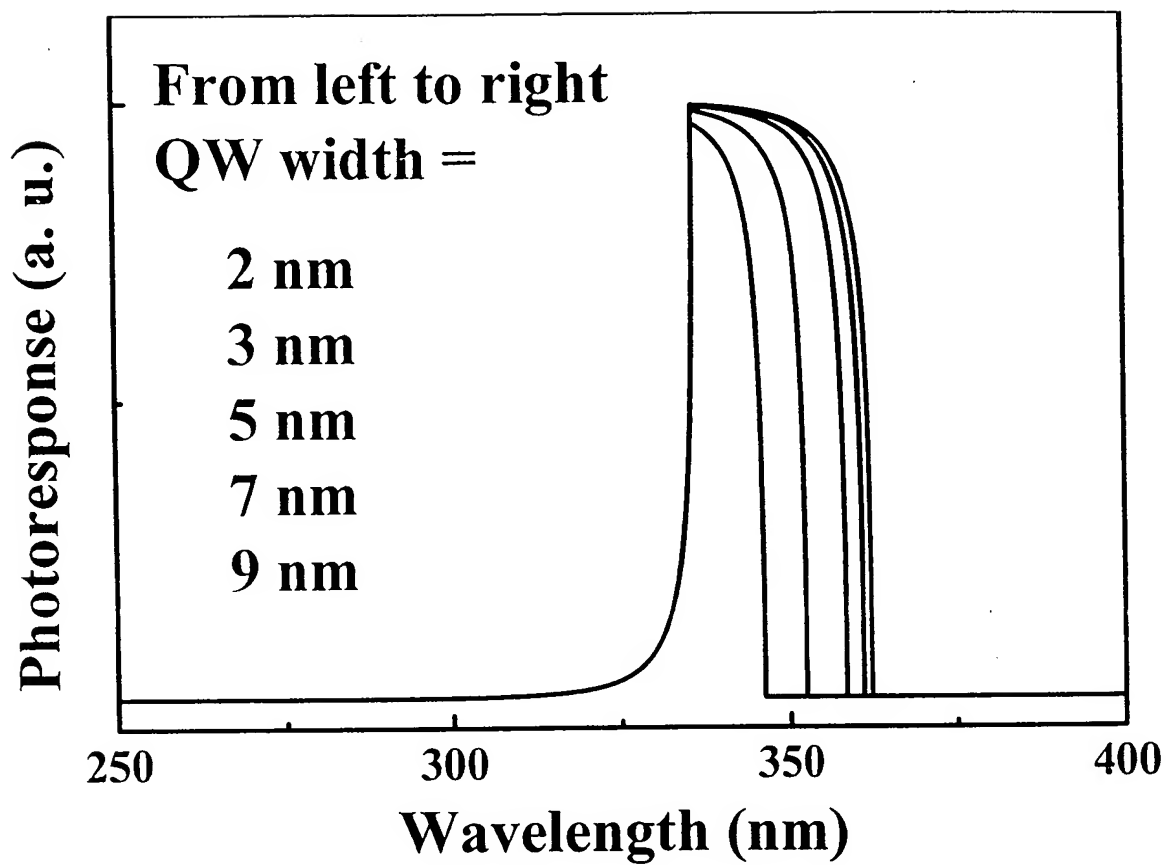


FIG. 5

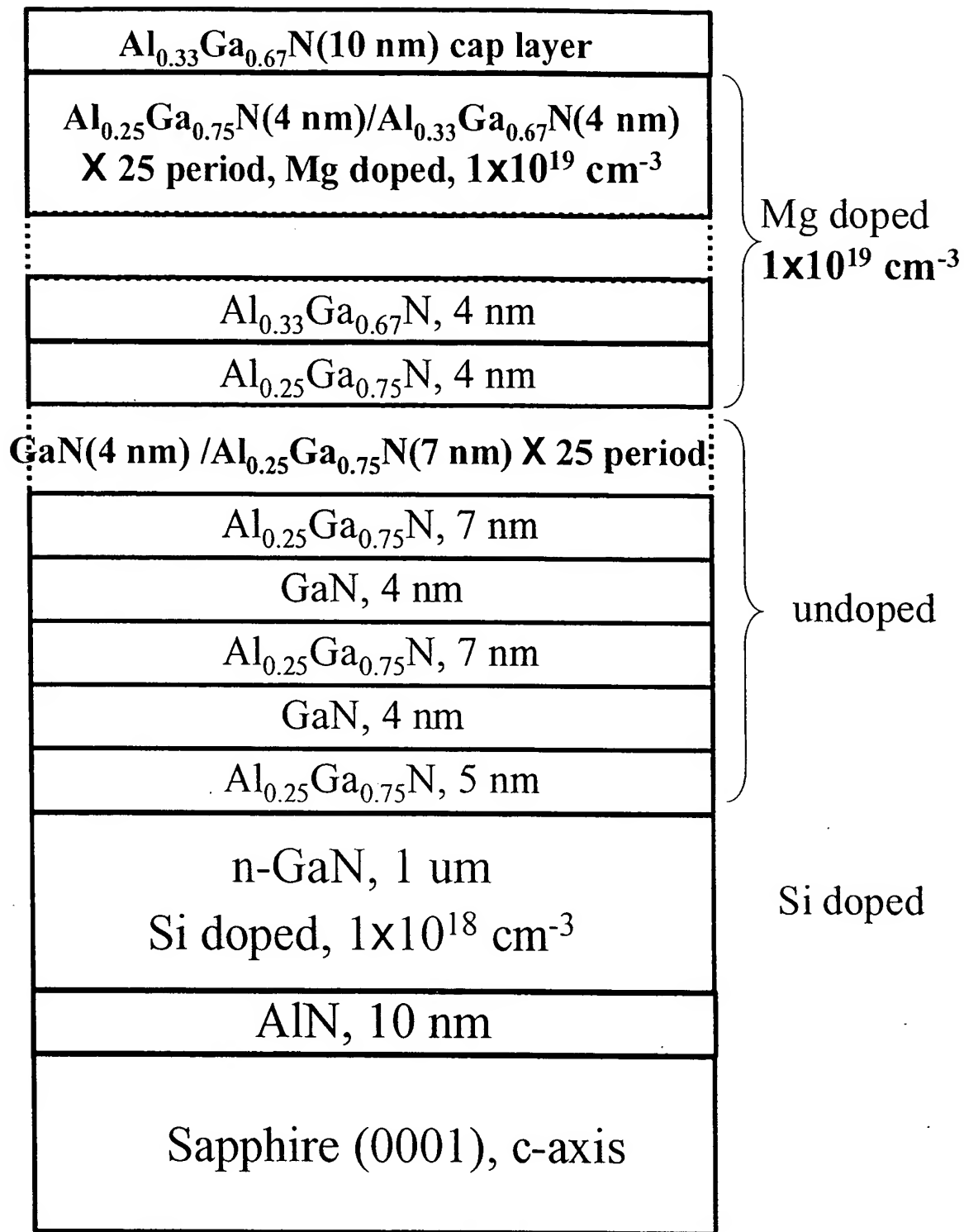


FIG. 6

n-Al _{0.2} Ga _{0.8} N, 1.5 μ m Si doped, 1×10^{18} cm ⁻³
Al _{0.27} Ga _{0.73} N, 5 nm
GaN, 4 nm
X 40 period QW
GaN, 4 nm
Al _{0.27} Ga _{0.73} N, 7 nm
GaN, 4 nm
Al _{0.27} Ga _{0.73} N, 7 nm
GaN, 4 nm
Al _{0.27} Ga _{0.73} N, 5 nm
AlN, 10 nm
p- 6H-SiC, 1×10^{18} cm ⁻³

FIG. 7

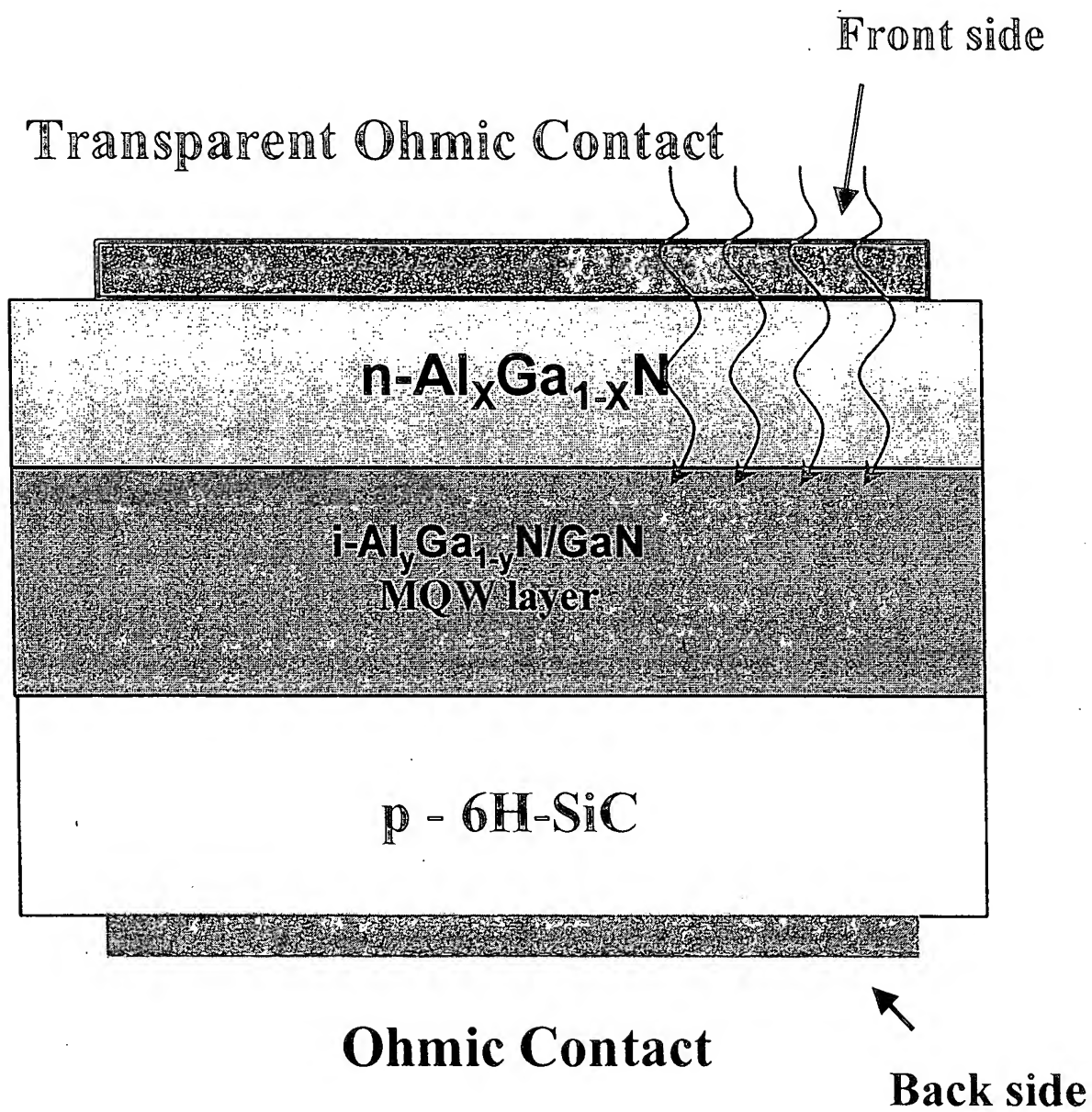


FIG. 8